

Search Notes

Application/Control No.

10/648,340

Examiner

W. Patty Chen

Applicant(s)/Patent under
Reexamination

OGISHIMA ET AL.

Art Unit

2871

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
349/129 combined with key words search of all databases in EAST	12/7/2006	WPC
citations search of relevant references	12/7/2006	WPC
349/129 combined with 349/110 search	12/7/2006	WPC